



PATENT

Case Docket No. STANF.131CP2

Date: March 2, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Aydogan Ozcan et al.  
Appl. No. : 10/645,331  
Filed : August 21, 2003  
For : METHOD OF MEASURING A  
PHYSICAL FUNCTION USING  
A COMPOSITE FUNCTION  
WHICH INCLUDES THE  
PHYSICAL FUNCTION AND  
AN ARBITRARY REFERENCE  
FUNCTION  
Examiner : Unknown  
Group Art Unit : 2124

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

March 2, 2004

(Date)

Bruce S. Itchkawitz, Reg. No. 47,677

TRANSMITTAL LETTER

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) A Supplemental Information Disclosure Statement.
- (X) A PTO Form 1449 with four (4) references, with copies of the references.
- (X) Return prepaid postcard.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.

Bruce S. Itchkawitz  
Registration No. 47,677  
Attorney of Record  
Customer No. 20,995  
(949) 760-0404



## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Applicants : Aydogan Ozcan et al.  
App. No. : 10/645,331  
Filed : August 21, 2003  
For : METHOD OF MEASURING A PHYSICAL  
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ARBITRARY REFERENCE FUNCTION  
Examiner : Unknown  
Group Art Unit : 2124

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing four (4) references that are also enclosed.

This Supplemental Information Disclosure Statement is being filed before the mailing date of a final action under 37 C.F.R. § 1.113 and before the mailing date of a Notice of Allowance under § 1.311. A certification under 37 C.F.R. § 1.97(e) is set forth below. Thus, no fee is required as set forth in 37 C.F.R. § 1.97(c).

CERTIFICATION UNDER 37 C.F.R. § 1.97(e)(1)

I hereby certify that reference Nos. 2 and 3 contained in this Statement were first cited in an Invitation to Pay Additional Fees from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing of this Supplemental Information Disclosure Statement. The Invitation to Pay Additional Fees is also cited herein, and a copy enclosed.

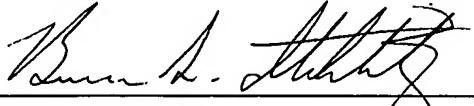
Appl. No. : 10/645,331  
Filed : August 21, 2003

Docket No. STANF.131CP2  
Customer No. 20,995

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 3/2/04

By: 

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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
STANF.131CP2APPLICATION NO.  
10/645,331SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT  
BY APPLICANTAPPLICANTS  
Aydogan Ozcan et al.FILING DATE  
August 21, 2003GROUP  
2124

(USE SEVERAL SHEETS IF NECESSARY)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER  
INITIAL

## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	1	Kashyap, Raman, et al., <i>Phase-matched second harmonic generation by periodic poling of fused silica</i> , <u>APPLIED PHYSICS LETTERS</u> , Vol. 64, No. 11, 14 March 1994, pp. 1332-1334.
	2	Ozcan, A., et al., <i>Inverse Fourier transform technique to determine second-order optical nonlinearity spatial profiles</i> , <u>APPLIED PHYSICS LETTERS</u> , Vol. 82, No. 9, 3 March 2003, pp. 1362-1364.
	3	"Invitation to Pay Additional Fees" from the International Searching Authority regarding corresponding PCT Application No. PCT/US 03/26311, filed August 21, 2003, including Annex to Form PCT/ISA/206, "Communication Relating to the Results of the Partial International Search."
	4	Qui, Mingxin, et al., <i>Erratum: "Double fitting of Marker fringes to characterize near-surface and bulk second-order nonlinearities in poled silica,"</i> <u>APPLIED PHYSICS LETTERS</u> , Vol. 77, No. 23, 4 December 2000, p. 3863.

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EXAMINER

DATE CONSIDERED

\*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.